National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name : EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard ISO/IEC 17025:2017

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S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
Permanent Facility				
1	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61000-6-1
2	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Voltage Fluctuation & Flicker Test	IEC 60601-1-2
3	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic equipment system/Subsystem	Conducted Emission	CE 101-MIL 461 F
4	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic equipment system/Subsystem	Conducted Emission	CE 102-MIL 461 E
5	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Emission	CE 102-MIL 461 F
6	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Emission	CE 101-MIL 461 E
7	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Bulk Cable Injection	CS 114-MIL 461 E
8	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Bulk cable Injection Impulse Excitation	CS 115 -MIL 461 F
9	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Bulk cable Injection Impulse Excitation	CS 115-MIL 461 E
10	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Bulk Cable Injection	CS 114-MIL 461 F
11	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Damped Sinusoidal Transients, Cable and Power Lead	CS 116 MIL 461 E
12	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Damped Sinusoidal Transients, Cable and Power Lead	CS 116-MIL 461 F
13	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Power Leads	CS101-MIL 461 E
14	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Power Leads	CS101-MIL 461 F
15	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Structure Current	CS 109-MIL 461 E
16	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Structure Current	CS 109-MIL 461 F

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17	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	CISPR 24
18	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 55024
19	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-6-1
20	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-6-2
21	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 61000-6-1
22	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55011
23	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55014-1
24	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55015
25	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 61000-6-3
26	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 61000-6-3
27	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 61326-1
28	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	DC Voltage dips, Short Interruption & Voltage Variations Immunity Test	BS EN 61000-4-29
29	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 61000-4-2
30	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61000-6-2
31	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61326-1
32	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 55014-2
33	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 55024

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34	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 55024
35	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	CISPR 14-2
36	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	CISPR 24
37	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	CISPR 35
38	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 60601-1-2
39	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61000-6-1
40	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 61000-4-5
41	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61000-6-2
42	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 55024
43	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 55014-2
44	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 60601-1-2
45	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 61000-4-8
46	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 61000-6-1
47	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 61000-6-2
48	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	CISPR 24
49	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	CISPR 35
50	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 60601-1-2
51	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61000-6-1
52	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61326-1

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53	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	CISPR 32
54	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 55011
55	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 55014-1
56	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 55022
57	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 60601-1-2
58	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 61000-6-4
59	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	CISPR 14-1
60	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	CISPR 22
61	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 60601-1-2
62	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 61000-6-3
63	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 61000-6-4
64	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 61326-1
65	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 61000-6-2
66	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	CISPR 24
67	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 60601-1-2
68	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 55014-2
69	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 55024
70	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 60601-1-2
71	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 61000-4-3

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72	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 61000-6-1
73	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	CISPR 14-2
74	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	CISPR 35
75	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61000-6-2
76	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61326-1
77	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 55014-2
78	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 61000-4-11
79	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	CISPR 14-2
80	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61326-1
81	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 60601-1-2
82	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	CISPR 35
83	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	BS EN 60601-1-2
84	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	BS EN 61000-3-3
85	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 61000-6-3
86	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55022
87	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 60601-1-2
88	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 61000-6-4

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89	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	CISPR 11
90	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	CISPR 14-1
91	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	CISPR 22
92	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	FCC Part 15B & 18
93	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 60601-1-2
94	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 61000-6-4
95	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 55014-2
96	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 55024
97	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 60601-1-2
98	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 61000-4-6
99	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 61000-6-1
100	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 61000-6-2
101	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	CISPR 14-2
102	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	CISPR 24
103	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	CISPR 35
104	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 60601-1-2
105	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 61000-4-6
106	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 61000-6-1
107	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 61000-6-2

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108	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	DC Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-4-29
109	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 55014-2
110	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 55024
111	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 60601-1-2
112	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 61000-4-4
113	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 61000-6-1
114	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 61000-6-2
115	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	CISPR 24
116	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	CISPR 35
117	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 60601-1-2
118	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61000-4-4
119	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61000-6-1
120	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61000-6-2
121	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61326-1
122	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 60601-1-2
123	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 61000-6-1
124	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 61000-6-2
125	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61000-4-2

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126	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 55014-2
127	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 55024
128	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 60601-1-2
129	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 61000-6-1
130	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 61000-6-2
131	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	CISPR 24
132	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	CISPR 24
133	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	CISPR 35
134	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	CISPR14-2
135	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 60601-1-2
136	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 61000-6-1
137	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 61000-6-2
138	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 61326-1
139	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy/Telecom Surge Immunity Test	IEC 61000-4-5
140	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61000-4-8
141	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	FCC Part 15B & 18
142	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Testing	CISPR 11
143	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61000-4-3
144	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Ring Wave Immunity Test	BS EN 61000-4-12

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145	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Ring Wave Immunity Test	IEC 61000-4-12
146	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-4-11
147	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 61000-6-2
148	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 60601-1-2
149	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	IEC 61000-3-3
150	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Conducted Emission	CISPR 15
151	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Conducted Emission	CISPR 32
152	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	BS EN 60601-1-2
153	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	BS EN 61000-3-2
154	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	BS EN 61000-6-3
155	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	IEC 60601-1-2
156	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	IEC 61000-6-3
157	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	IEC 61000-3-2
158	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronics products	Conducted RF Susceptibility Test	IEC 61326-1